Radiation Tolerant Electronics

Message from the Guest Editor

The main aim of this Special Issue is to seek high-quality submissions that highlight emerging applications, address recent breakthroughs in modeling radiation effects in advanced electronic devices and circuits, the design of radiation hardened analog, mixed-signal, RF and digital integrated circuits and radiation hardness testing methodologies. The topics of interest include, but are not limited to:

- Basic mechanisms of radiation effects in electronic devices
- Compact modeling of radiation effects and circuit/layout level optimization (TID and SEE)
- Radiation effects in power devices/circuits
- Design of radiation hardened integrated circuits (analog/RF/mixed-signal/digital)
- Radiation hardening and fault tolerance in FPGAs
- Radiation hardness assurance testing

Welcome to contribute!